



HIPPI-6400 Optics Ad Hoc Group

MTP Technology Review

October 6th, 1998

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Outline

Review of issues presented 8/98
Results of US Conec Investigation
Summary

Issues Presented 8/98

Durability testing of MT

In some samples found:

- Chipping around guide pin holes
- Cracking of ferrule

Theory - due to non-parallel guide pins

**Issue - Are parts tested outside IEC spec.,
or is IEC spec. insufficient?**

US Conec Investigation

Over 14 million MT ferrules installed since 1988

Over 500 hundred thousand MTP/MPO installed since 1993

Installations in North America, Japan, and Europe

First time these issues have been raised

US Conec Investigation

Examined parts tested by Siemens

6 MT ferrules and 2 guide pins

Ferrule dims. within IEC spec.

Pins bent and non-grooved

**See no problem with IEC spec. for ferrule
and pins**

US Conec Investigation

Next step - further investigation of MTP housing

- Want to ensure no problems with housing
- Examine MTP housings and adapters tested by Siemens
- Perform further MTP testing to try and repeat results

Summary

**Have not previously seen these issues
MT ferrules and pins meeting IEC spec.
Will further investigate MTP housing &
report at December HIPPI meeting**